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Application/Control No.	Applicant(s)/Patent under Reexamination	
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369	none	12/21/2006 updatadon 10/22/07	VP V Ø	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB) 369 (text search only see search history printout).	10/22/2007	VP		
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